

Negative Polarity Rod-Pinch Experimental Plan on RITS-6

Joshua J. Leckbee

**Radiography Workshop
22 – 24 May 2007**

*Work performed under the U.S./U.K contracts DE-AC52-06NA-25129/PALD 783 and DE-AC04-02AL-67817/PALD 760

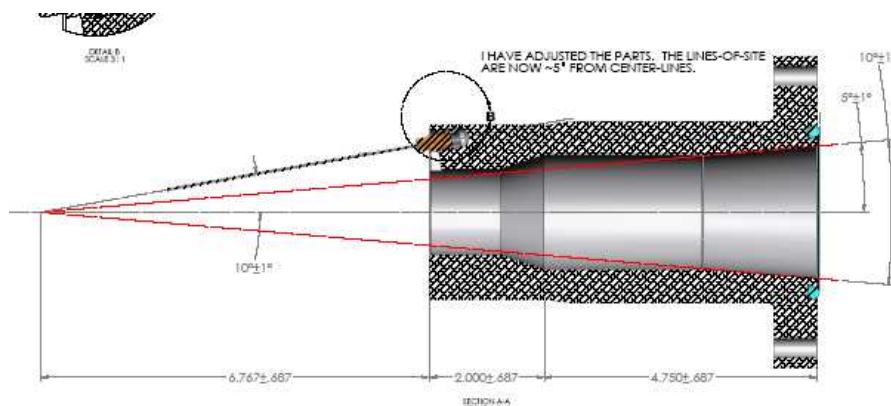
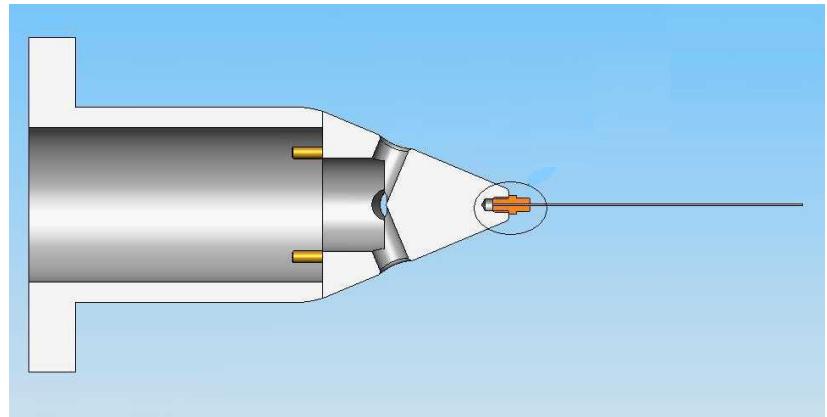
Sandia is a multiprogram laboratory operated by Sandia Corporation, a Lockheed Martin Company,
for the United States Department of Energy's National Nuclear Security Administration
under contract DE-AC04-94AL85000.

The export of this material to the U.K. is covered under the 1958 U.S./U.K. Mutual Defense agreement.



Standard on-axis anodes as well as angled anode rods will be fielded.

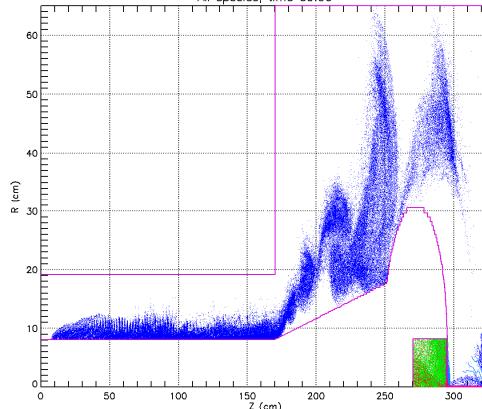
- Primary goals:
 - Demonstrate good diode impedance behavior
 - Extract dose on-axis and measure dose and spot
- The first few shots will use a “standard” on-axis rod.
- After good diode behavior is demonstrated, an angled rod will be fielded to facilitate on-axis dose and spot measurements.
- Both solid tungsten and aluminum tube with tungsten tips will be fielded.
- Angled rod will provide 4.5 degree half-angle line of sight.



Dustbin Modifications were studied to improve power flow.

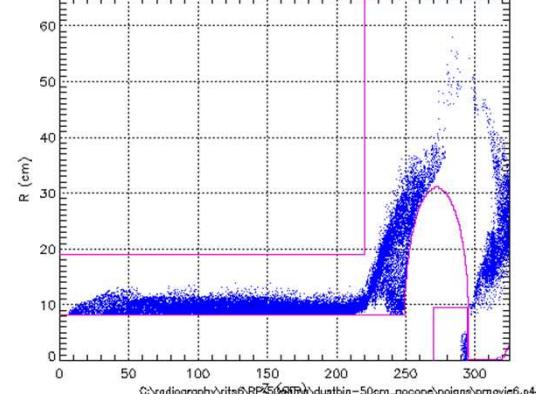
Normal Dustbin

Rod Pinch: cone, Rcone=1cm, Rrod=15cm RP_dustbin.5 w/ improved diag's, smaller AK: RP_dustbin.8.lsp - Mon A
All species; time 60.00

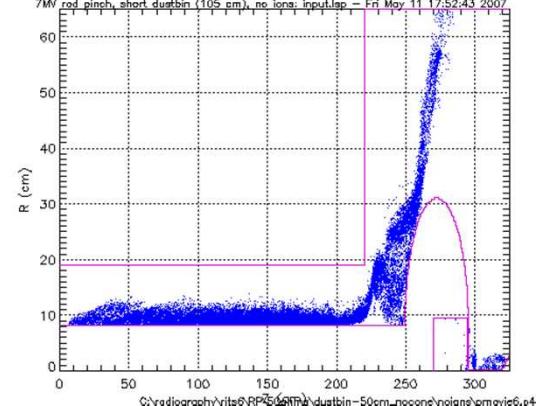


Shortened Dustbin

7MV rod pinch, short dustbin (105 cm), no ions; input.lsp - Fri May 11 17:52:43 2007
 $t = 55.20$ ns

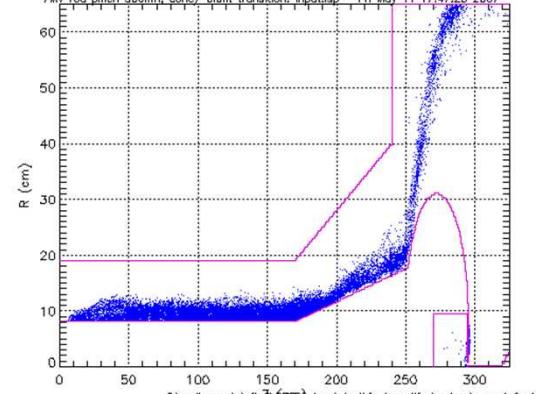


7MV rod pinch, short dustbin (105 cm), no ions; input.lsp - Fri May 11 17:52:43 2007
 $t = 59.10$ ns

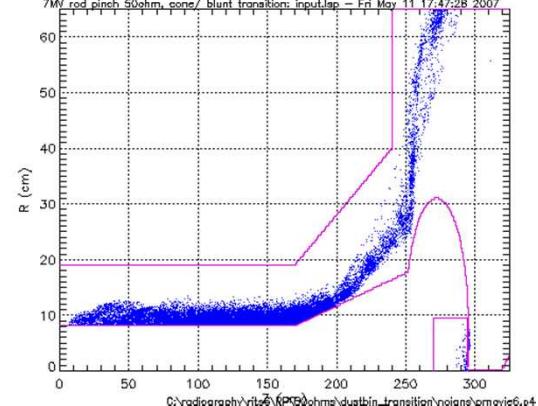


Tapered Transition

7MV rod pinch 50ohm, cone/ blunt transition; input.lsp - Fri May 11 17:47:28 2007
 $t = 55.20$ ns



7MV rod pinch 50ohm, cone/ blunt transition; input.lsp - Fri May 11 17:47:28 2007
 $t = 59.10$ ns



The tapered dustbin transition design will be fielded on the NPPR experiments.

- The tapered anode and cathode maintain almost constant impedance up to 10cm behind the knob.
- Field stress on the back of the knob is lower than the very short dustbin design.
- The dustbin modification should greatly reduce the effect of the power flow on the diode performance.

